NaioAFM

The leading compact AFM

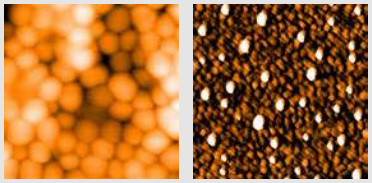
Compact and robust

Easy to use

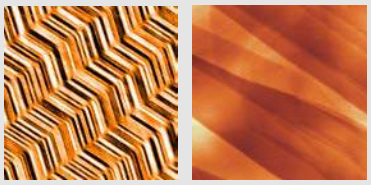
Real value for money

nanosurf

NaioAFM



Particle size. Left: Staphylococcus aureus bacterial sample. Scan size 5.0 µm. Right: Gold colloids. Scan size 1.5 µm.



Data storage. Digital backup tape with magnetically stored data, as revealed by MFM. Scan size 50 µm.

Atomic steps. HOPG. Single layer height is 0.34 nm. Image Z-range is 3.5 nm. Scan size 3.2 µm.

Cantilever exchange. Quick and simple cantilever exchange with the NaioAFM's flip-over scan head design and cantilever exchange tools.

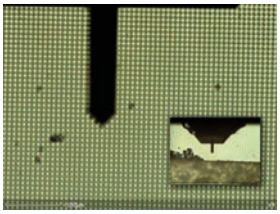
Setup. A NaioAFM, a USB cable, and a PC are all that you need!

All-in-one atomic force microscope for small samples and nanoeducation

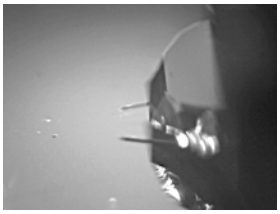
The NaioAFM is the ideal atomic force microscope for nanoeducation and small sample measurements. This all-in-one AFM system provides solid performance and easy handling, with a price tag and footprint that fit anyone and any place.

Key Features

- Integrated controllerXY-table, airflow shielding, and vibration isolation
- High resolution top view camera and side view sample observation built in
- Feature-complete: All standard operating modes available
- Simple cantilever exchange: no laser or detector adjustment required
- No system setup needed: just plug into your PC and start the software



Top view camera with zoom



Side view observation

Optional side view camera

NaioAFM specifications	
Max. scan range / scan height (resolution) (1)	70 µm (1.0 nm) / 14 µm (0.2 nm)
Static / Dynamic RMS Z-noise	typ. 0.4 nm (max. 0.8 nm) / typ. 0.3 nm (max. 0.8 nm)
Max. sample size / height	12 mm / 3.5 mm
Max. sample stage positioning range	12 mm travel in X and Y
Top view camera	2 × 1.5 mm FOV, 2 µm optical resolution, 5.0 MPixel color CMOS, 4× digital zoom, in-axis LED illumination
Side view observation	5 × 5 mm FOV, variable LED illumination (optional camera : 2 × 2 mm FOV, 1.3 MPixel monochrome CMOS)
Approach	4 mm linear motor, continuous or step-by-step approach
Imaging modes	Static Force, Dynamic Force, Phase Contrast, MFM, EFM
Advanced imaging modes (2)	Spreading Resistance, Force Modulation
Spectroscopy modes	Force–Distance, Amplitude–Distance, Voltage–Distance
Advanced spectroscopy modes (2)	Current–Voltage, Stop by end value, Fwd & Bwd pause
Lithography modes	Static Force, Dynamic Force, Oxidation
Advanced lithography modes (2)	Draw and load CAD vector graphics, Bitmap images
Remote control/add-ons (2)	Windows scripting interface: compatible with LabView, C#, Visual Basic, MatLab, and other software...
Operating system and PC requirements	Windows 7 or higher (32/64-bit), 1280x1024 px screen resolution, Core 2 CPU, 4 GB RAM, 1 free USB 2.0 port
Size (LWH) / Weight / Power	204×204×160 mm / 6.5 kg / 100–240 VAC (30 W)
Power	100–240 VAC, 50/60 Hz, 50 W

(1) Manufacturing tolerances are ±10%
(2) Naio Advanced Modes Option required

Compatible options and accessories
NaioAFM Side View Camera, Naio Advanced Modes Option, Isostage Adapters for Naio, AFM Extended Sample Kit

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